

United States Patent [19]

Shintani

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[45] Date of Patent: **** Feb. 27, 1990**

[54] **TWIN-NIBBED MARKING INSTRUMENT**

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[**] Term: **14 Years**

[21] Appl. No.: **43,198**

[22] Filed: **Apr. 24, 1987**

[52] U.S. Cl. **D19/36; D19/41;**
D19/43; D19/51

[58] Field of Search **D19/35, 36, 41-51,**
D19/54-58; 401/17, 18, 34, 195

[56] **References Cited**

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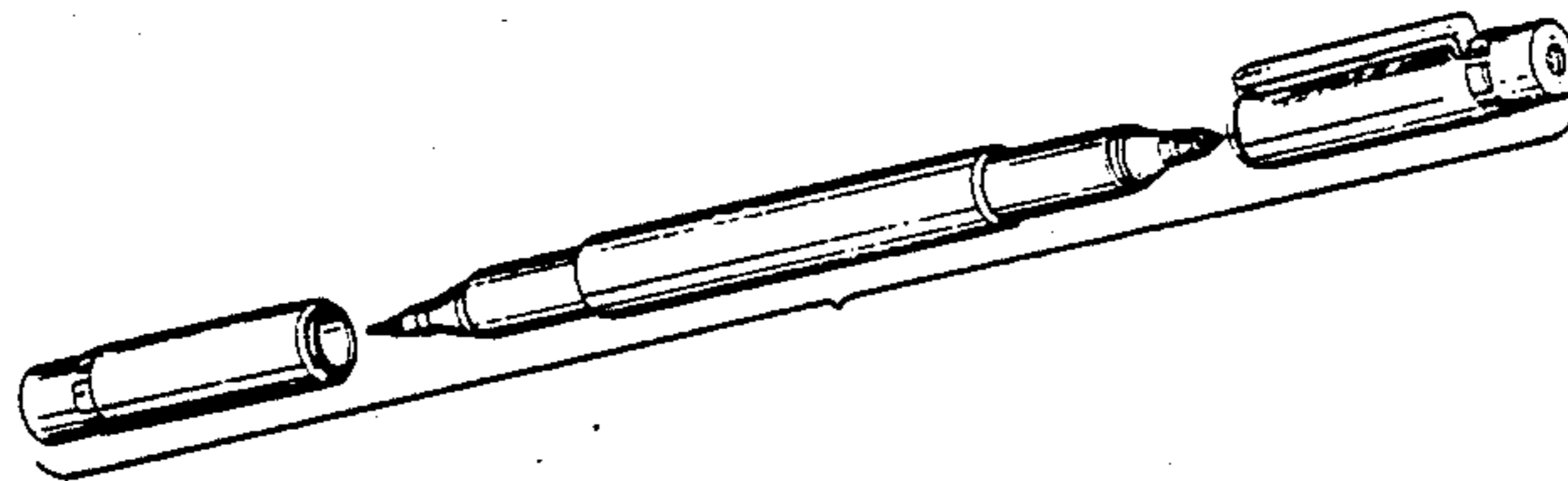
Primary Examiner—James R. Largen
Assistant Examiner—Martha Thompson
Attorney, Agent, or Firm—Michael J. Striker

[57] **CLAIM**

The ornamental design for a twin-nibbed marking instrument, as shown and described.

DESCRIPTION

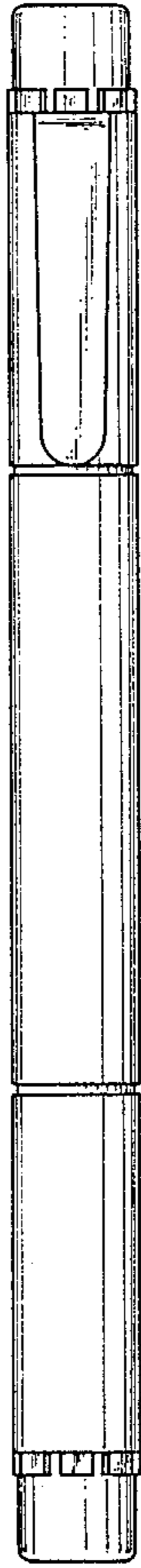
FIG. 1 is a front elevational view of a twin-nibbed marking instrument showing my new design;
FIG. 2 is a rear elevational view;
FIG. 3 is a right side elevational view;
FIG. 4 is a left side elevational view;
FIG. 5 is a top plan view;
FIG. 6 is a bottom plan view; and
FIG. 7 is a perspective view on a reduced scale in an exploded condition.



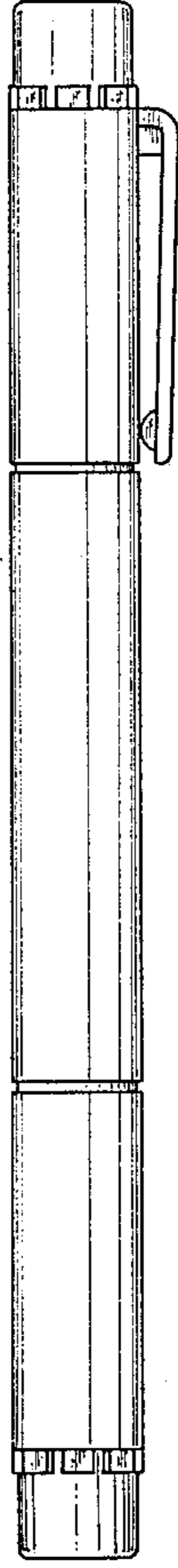
FIG_2



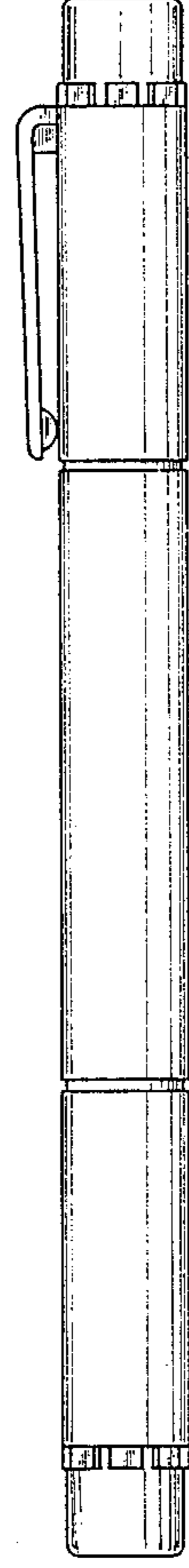
FIG_1



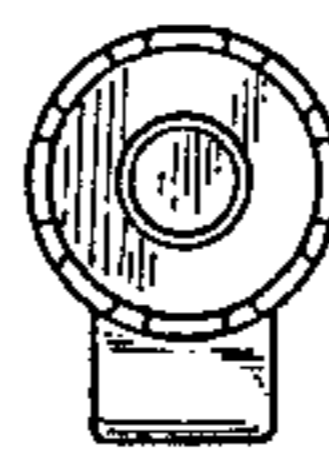
FIG_4



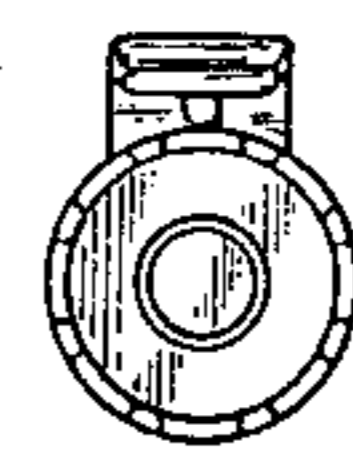
FIG_3



FIG_5



FIG_6



FIG_7

